

4 - 14 GHz Balanced LNA



Self Bias



Gate Bias

Key Features

- Frequency Range: 4 – 14.2 GHz
- 2.3 dB Nominal Noise Figure
- 25 dB Nominal Gain
- 15 dB AGC Range
- 13 dBm Nominal P1dB
- 24dBm Nominal OIP3
- Bias: 5 V, 160 mA Gate Bias
5 V, 90 mA Self Bias
- Package Dimensions:
4.0 x 4.0 x 0.9 mm

Primary Applications

- X-Band Radar
- EW, ECM
- Point-to-Point Radio

Product Description

The TriQuint TGA2512-SM is a packaged X-band balanced LNA with AGC amplifier for EW, ECM, and RADAR receiver or driver amplifier applications. The TGA2512-SM provides excellent noise performance with typical midband NF of 2.3dB, and high gain, 25dB from 4-14.2GHz

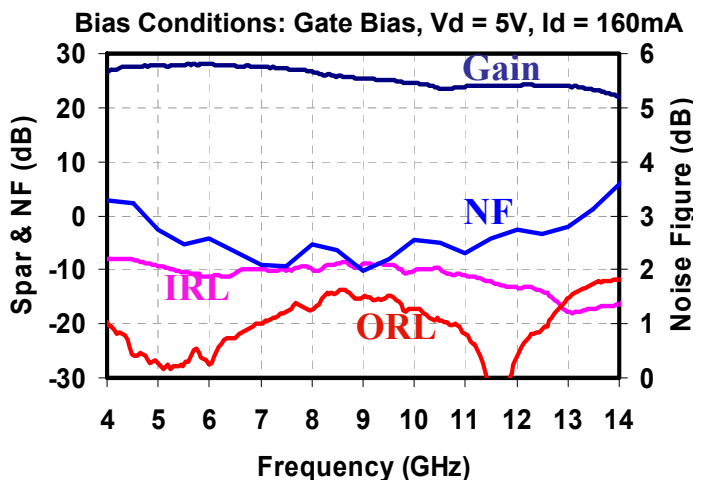
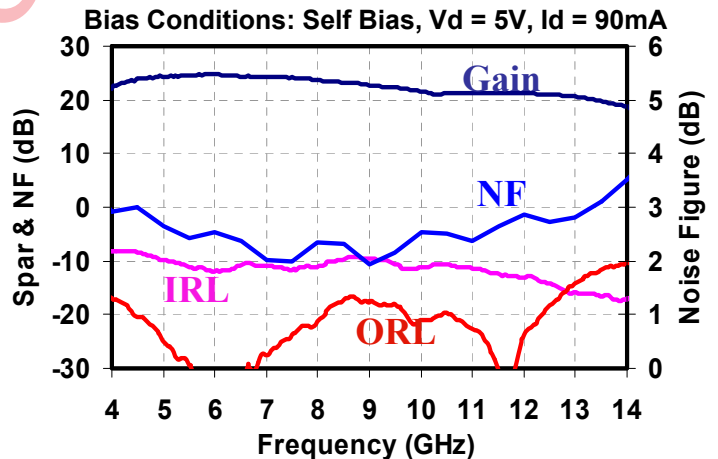
The TGA2512-SM is designed for maximum ease of use. TGA2512-SM can handle up to 21dBm input power reliably, while the build-in gain control provides 15dB of typical gain control range. The part can be used in self-biased mode, with a single +5V supply connection, or in gate biased mode, allowing the user to control the current for a particular application.

In self-biased mode the TGA2512-SM achieves 6dBm typical P1dB, while in gate-biased mode the typical P1dB is over 13dBm.

Lead-Free & RoHS compliant.

Evaluation boards are available.

Measured Data



Datasheet subject to change without notice

TABLE I
MAXIMUM RATINGS 1/

SYMBOL	PARAMETER	VALUE	NOTES
V _d	Drain Voltage	Gate Bias: [4 + (0.009)(I _d)] V	<u>2/</u> <u>3/</u>
		Self Bias: [3.5 + (0.022)(I _d)] V	
V _g	Gate Voltage Range	-1 TO +0.5 V	
I _d	Drain Current (gate biased)	240 mA	<u>2/</u>
I _g	Gate Current	7.04 mA	
P _{IN}	Input Continuous Wave Power	21 dBm	
P _D	Power Dissipation	1.56 W	<u>2/</u> <u>4/</u>
T _{CH}	Operating Channel Temperature	200 °C	<u>5/</u>
	Mounting Temperature (30 Seconds)	260 °C	
T _{STG}	Storage Temperature	-65 to 150 °C	

1/ These ratings represent the maximum operable values for this device.

2/ Combinations of supply voltage, supply current, input power, and output power shall not exceed P_D.

3/ Unit for I_d is mA

4/ When operated at this bias condition with a base plate temperature of 85 °C, the median life is 9.3E4 hours.

5/ Junction operating temperature will directly affect the device median time to failure (T_m).

For maximum life, it is recommended that junction temperatures be maintained at the lowest possible levels.

TABLE II-A
ELECTRICAL CHARACTERISTICS

(Ta = 25 °C, Nominal)

PARAMETER	Self Bias TGA2512-1-SM	Gate Bias TGA2512-2-SM	UNITS
Frequency Range	4 – 14.2	4 – 14.2	GHz
Drain Voltage, Vd	5.0	5.0	V
Drain Current, Id	160	160	mA
Gate Voltage, Vg	-	-0.1	V
Small Signal Gain, S21	22	25	dB
Input Return Loss, S11	-10	-10	dB
Output Return Loss, S22	-20	-20	dB
Noise Figure, NF	2.3	2.3	dB
Output Power @ 1dB Gain Compression, P1dB	6	13	dBm
OIP3	16	24	dBm
Temperature Gain Coefficient	-0.02	-0.02	dB/°C

Note: Table II Lists the RF Characteristics of typical devices as determined by fixtured measurements.

TABLE II-B
TGA2512-2-SM ELECTRICAL CHARACTERISTICS

(Vd=5V, Id=160mA, Vctrl=0V, Ta = 25 °C, Nominal)

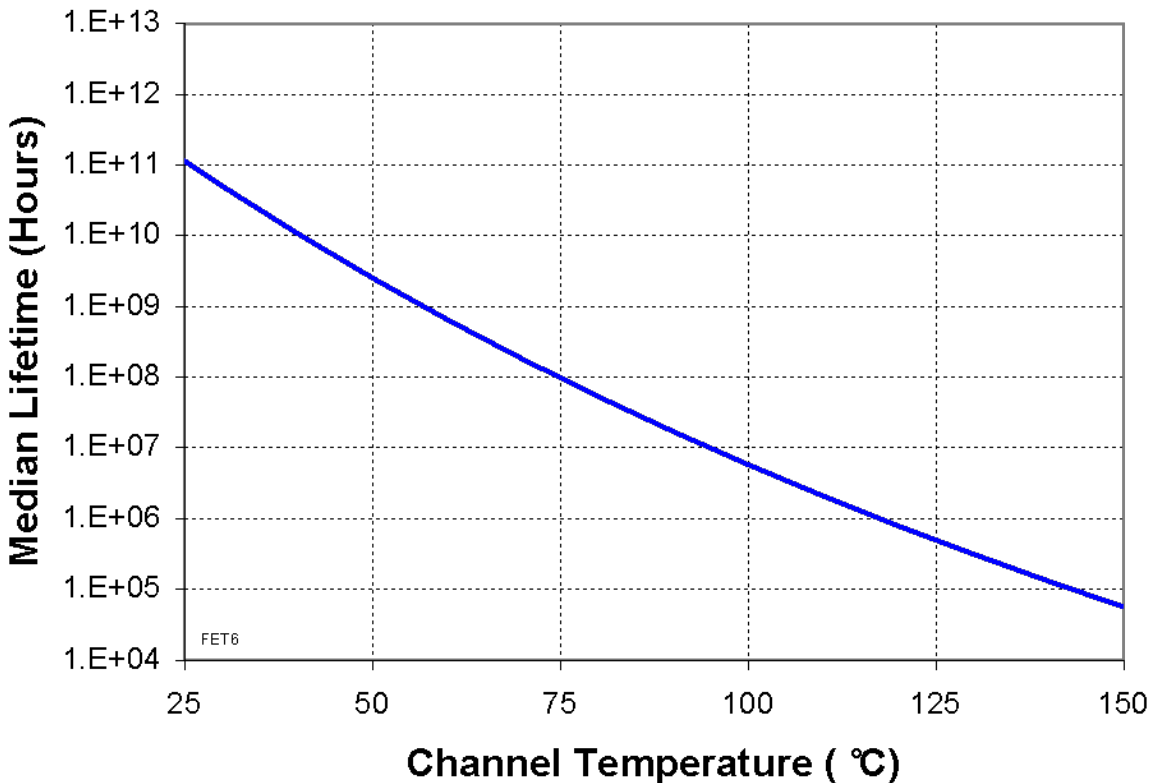
PARAMETER	Min	Typ	Max	UNITS
Frequency Range	11		14.2	GHz
Drain Current, Id		160	200	mA
Gate Voltage, Vg	-0.4	-0.1	0.2	V
Small Signal Gain, S21	19	24		dB
Input Return Loss, S11	-7	-12		dB
Output Return Loss, S22	-7	-12		dB
Noise Figure, NF		3	4.5	dB
Output Power @ 1dB Gain Compression, P1dB	10	13		dBm
OIP3	16	22		dBm

**TABLE III
THERMAL INFORMATION**

PARAMETER	TEST CONDITIONS	T _{CH} (°C)	θ _{JC} (°C/W)	T _m (HRS)
θ _{JC} Thermal Resistance (channel to Case)	Vd = 5 V Id = 160 mA Gate Bias Pdiss = 0.80 W	115	37.6	1.3E+6
θ _{JC} Thermal Resistance (channel to Case)	Vd = 5 V Id = 90 mA Self Bias Pdiss = 0.45 W	97.7	28.2	7.2E+6

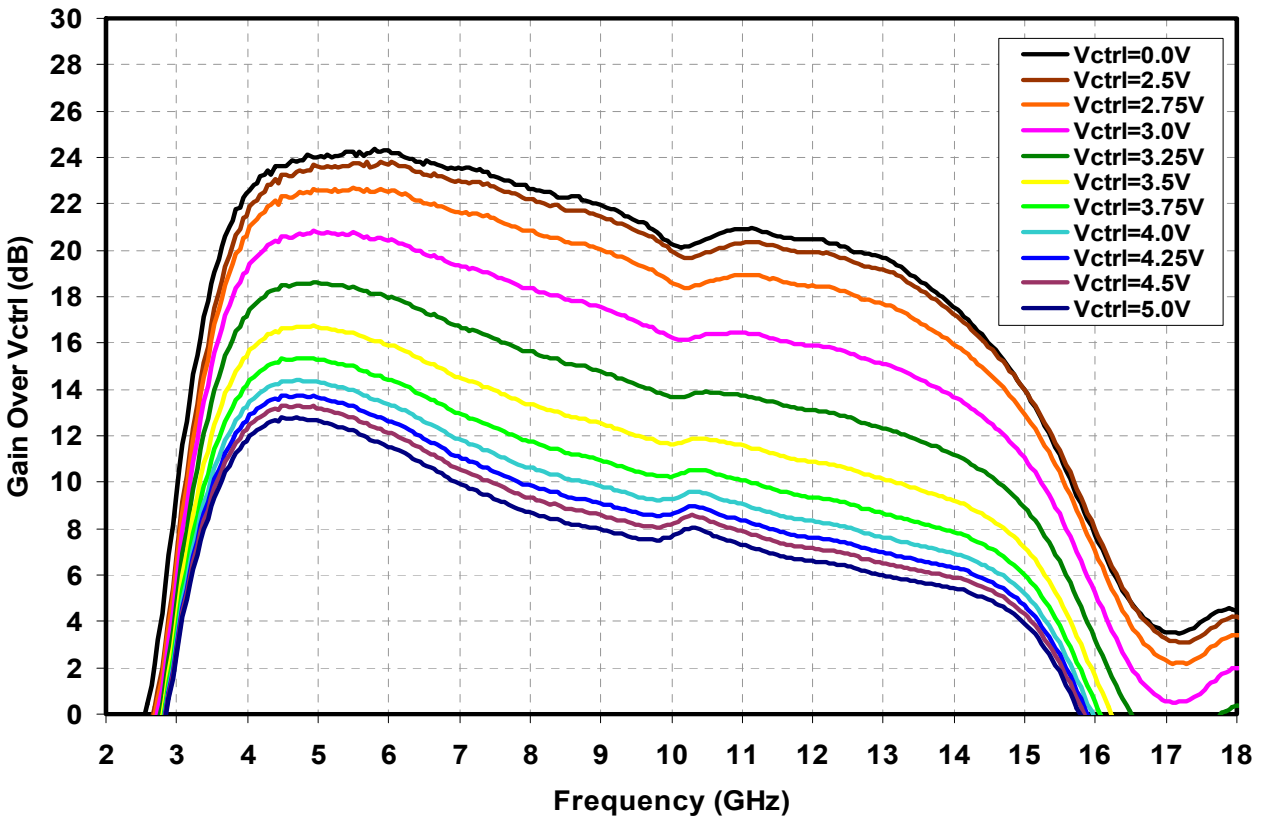
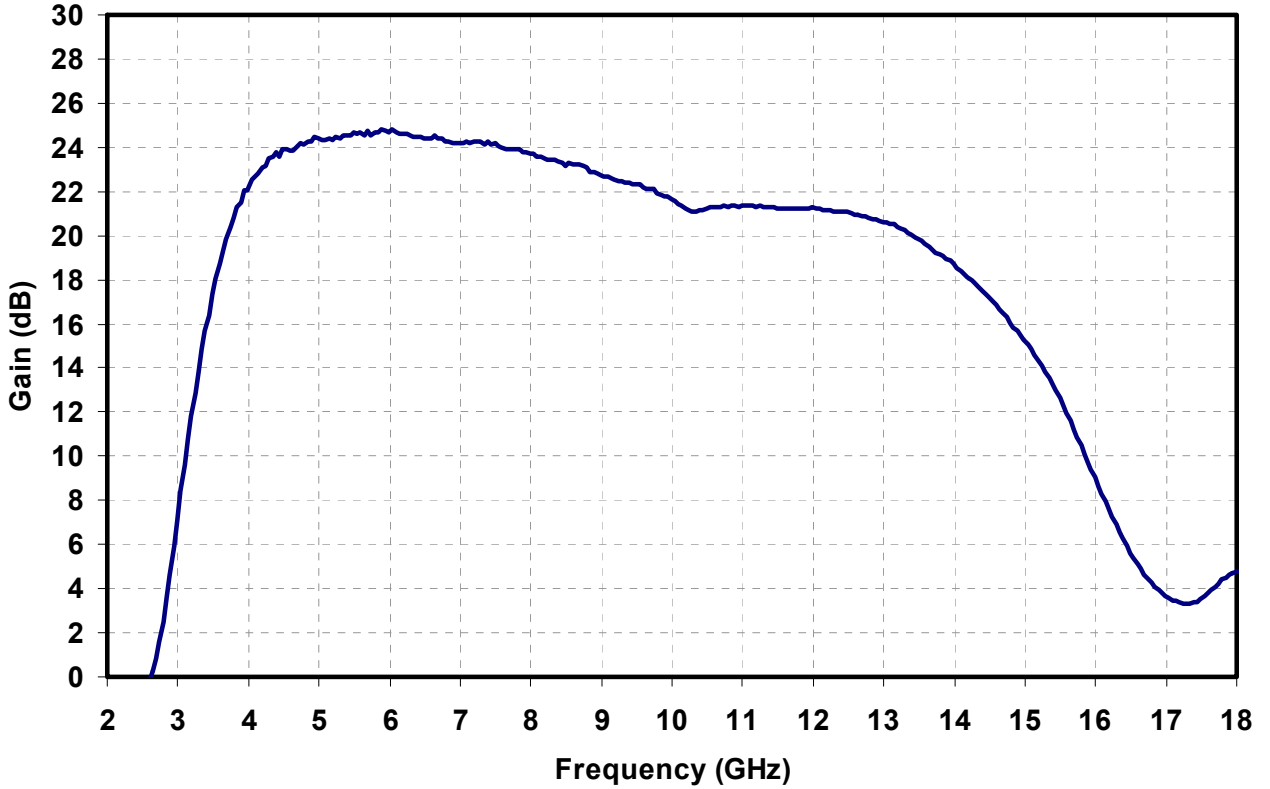
Note: Worst case condition with no RF applied, 100% of DC power is dissipated, Case Temperature at 85 °C

Median Lifetime (Tm) vs. Channel Temperature



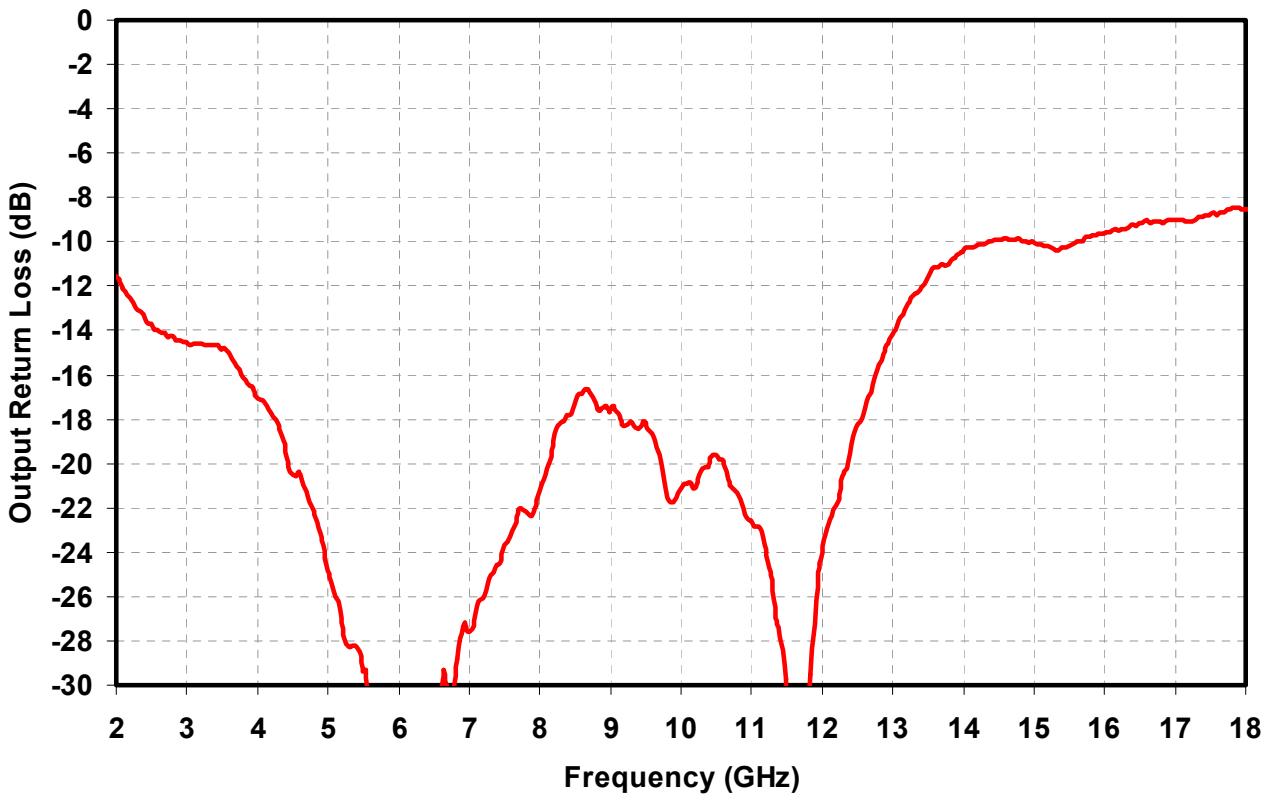
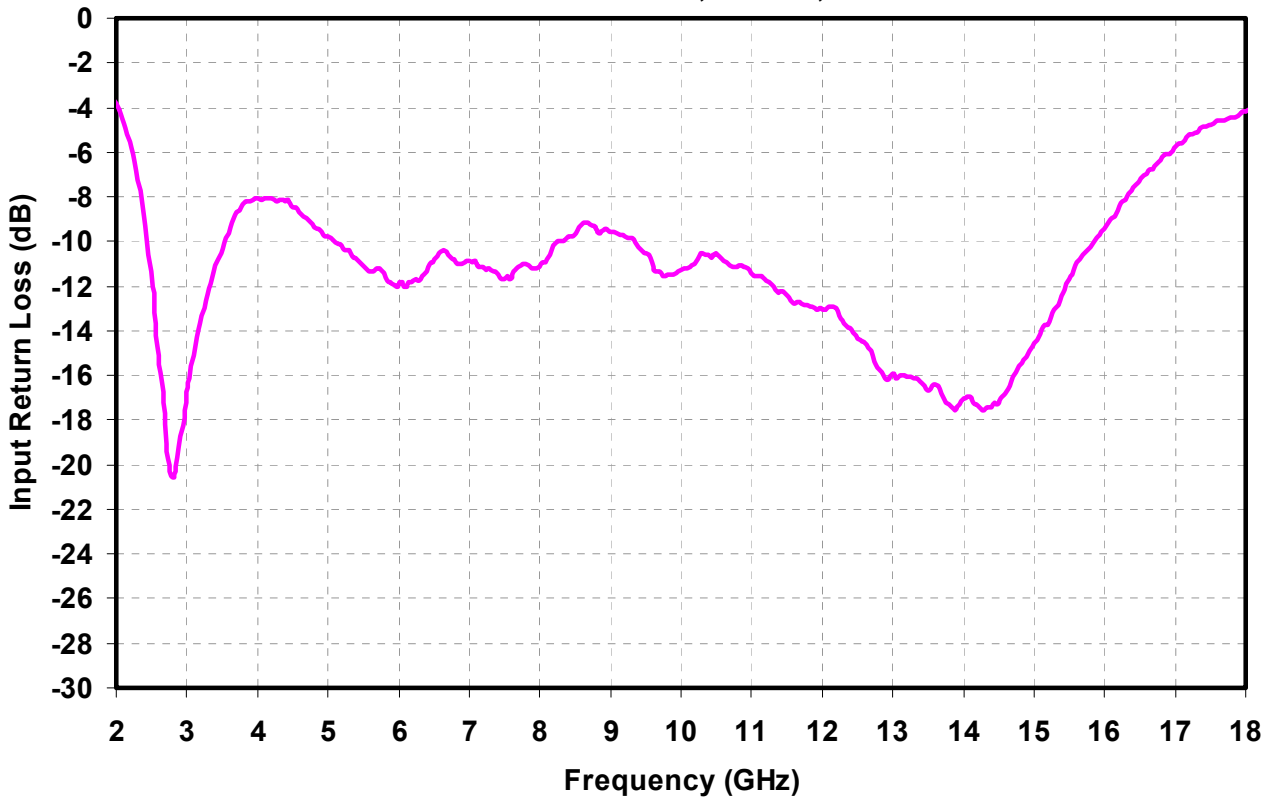
Measured Data

Bias Conditions: **Self Bias**, $V_d = 5\text{ V}$, $I_d = 90\text{ mA}$



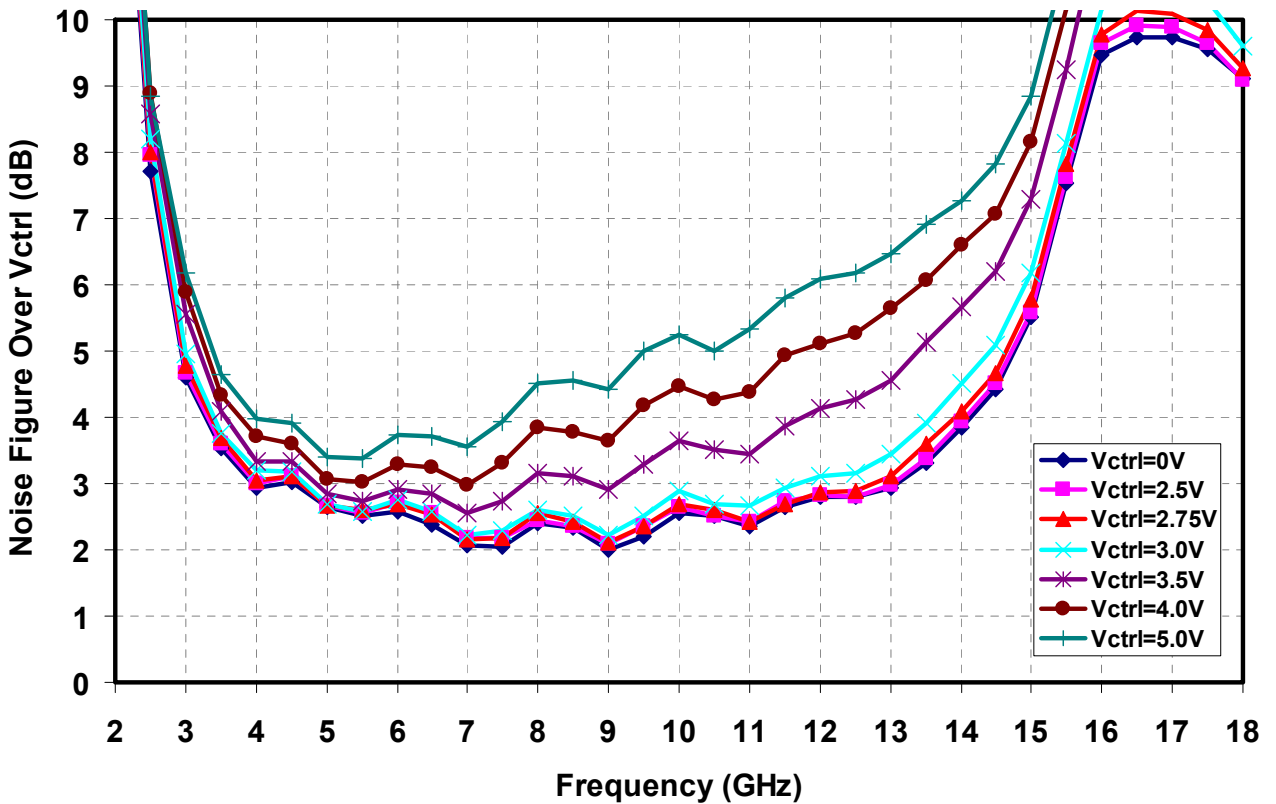
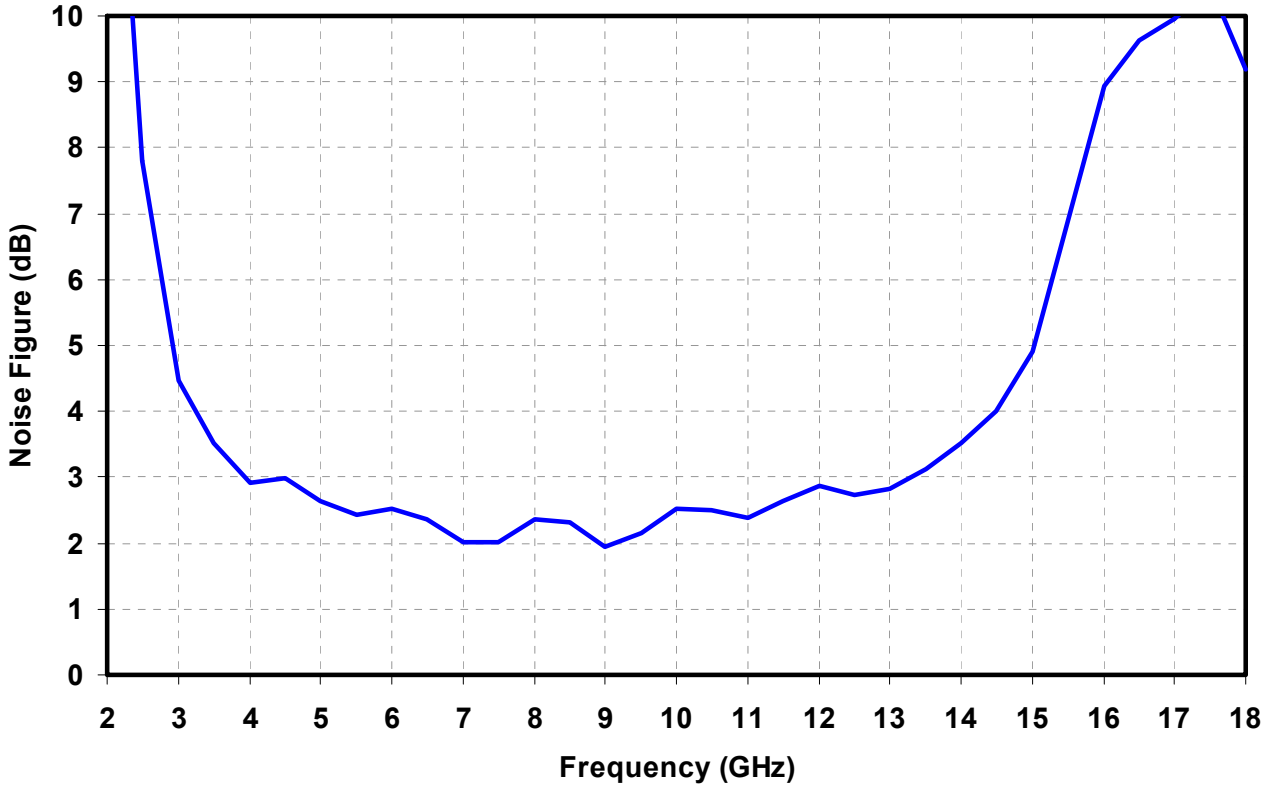
Measured Data

Bias Conditions: **Self Bias**, $V_d = 5\text{ V}$, $I_d = 90\text{ mA}$



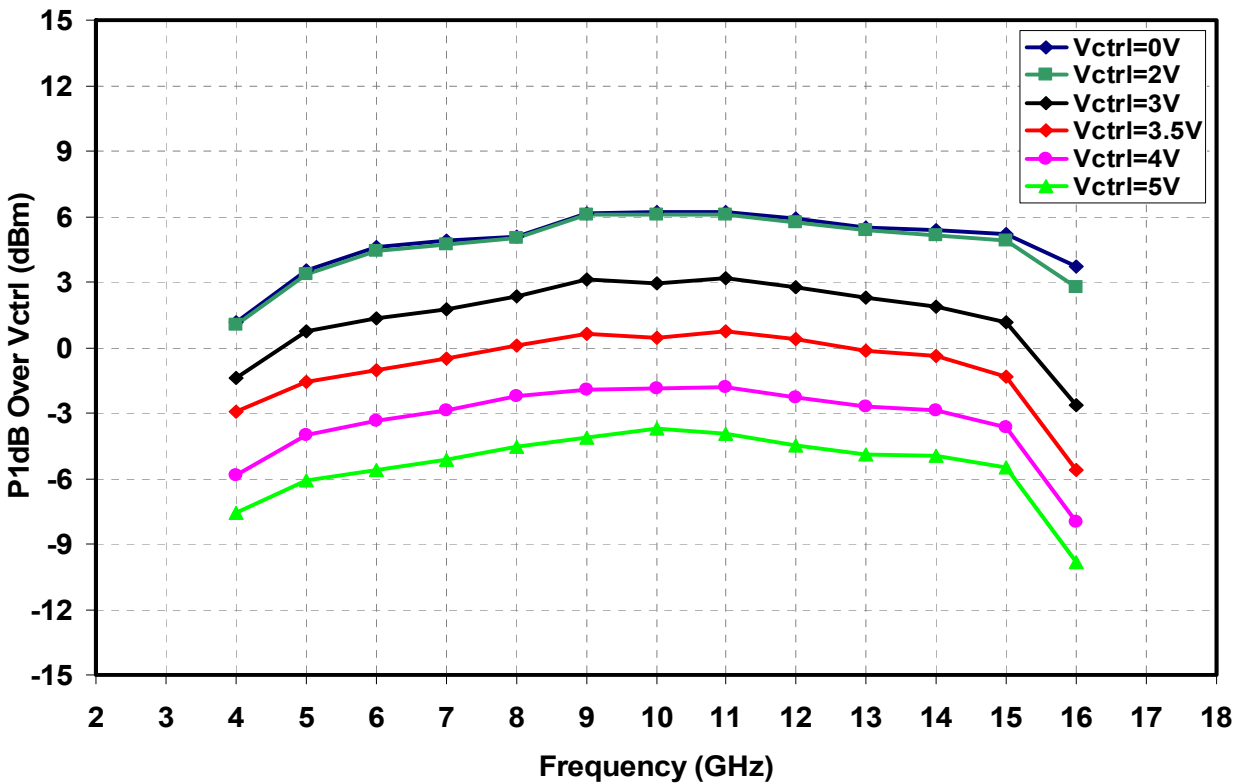
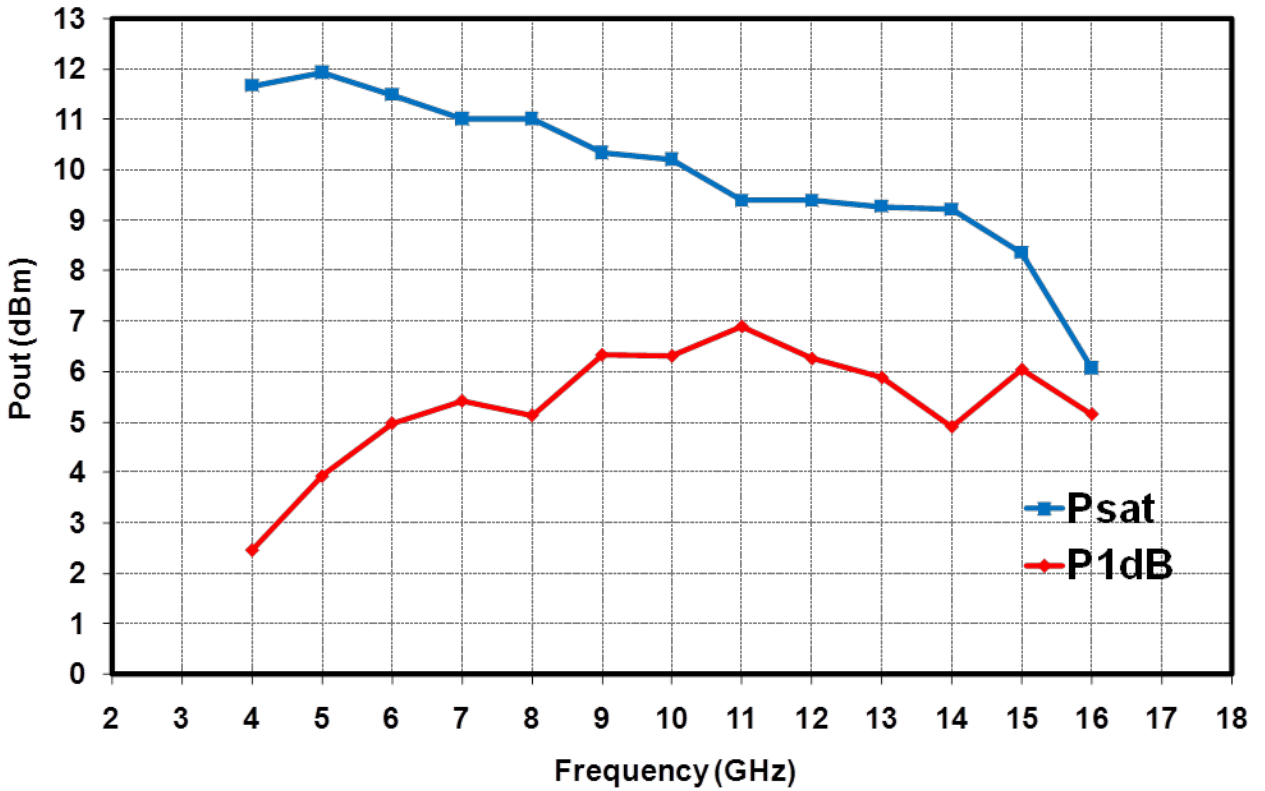
Measured Data

Bias Conditions: **Self Bias**, $V_d = 5\text{ V}$, $I_d = 90\text{ mA}$



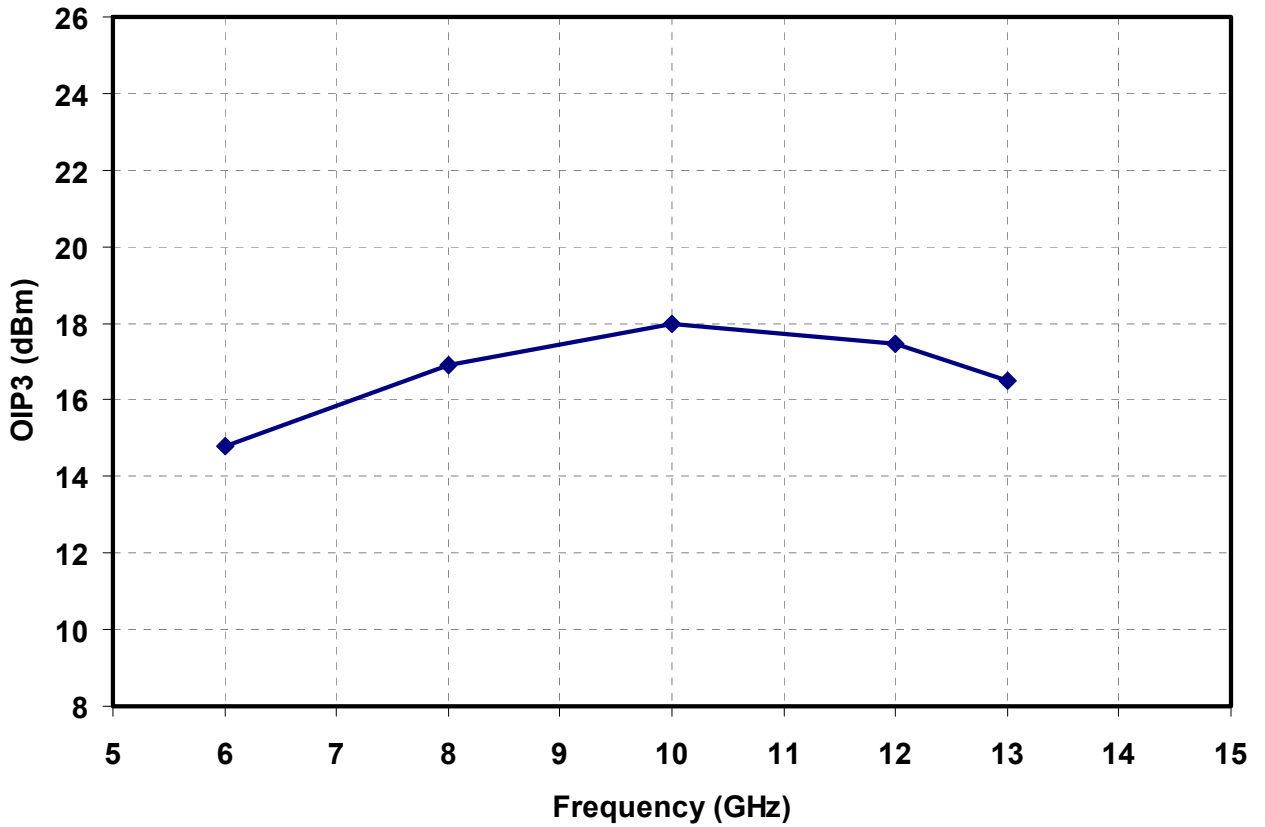
Measured Data

Bias Conditions: **Self Bias**, $V_d = 5\text{ V}$, $I_d = 90\text{ mA}$



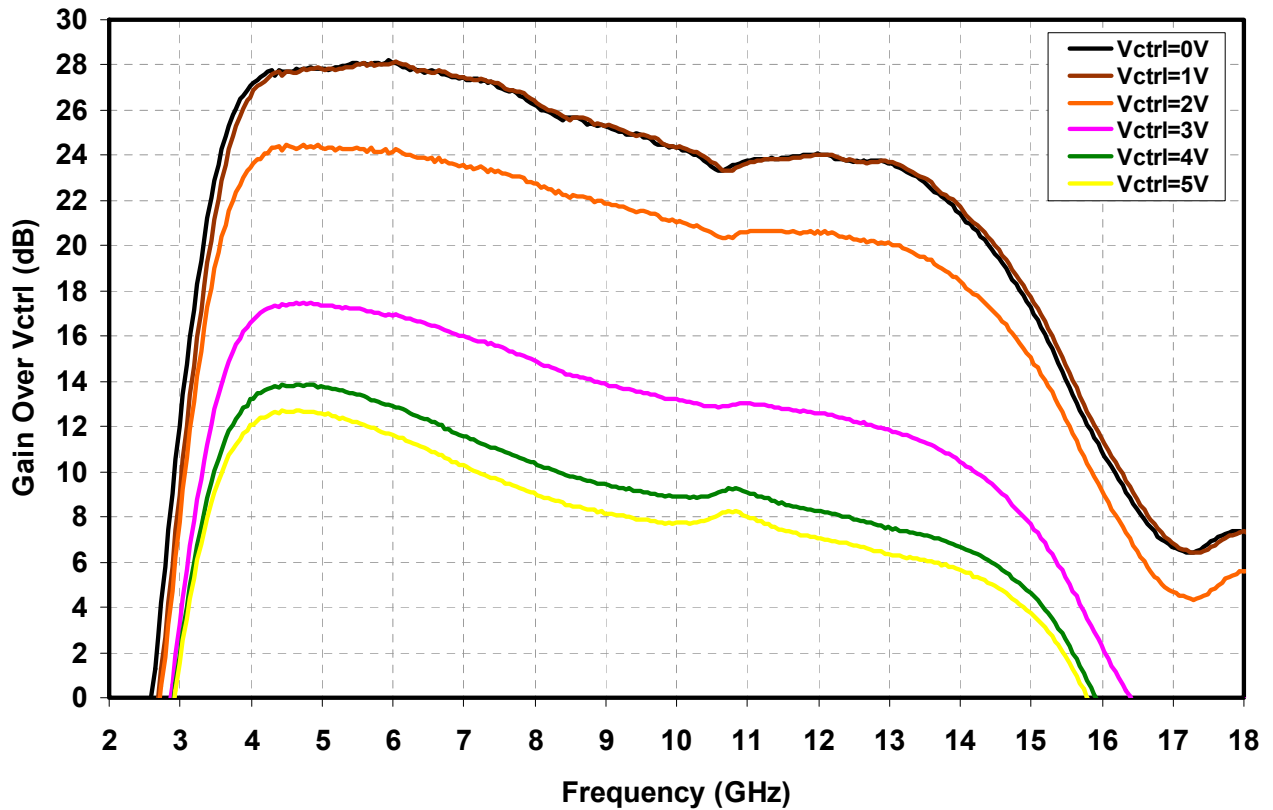
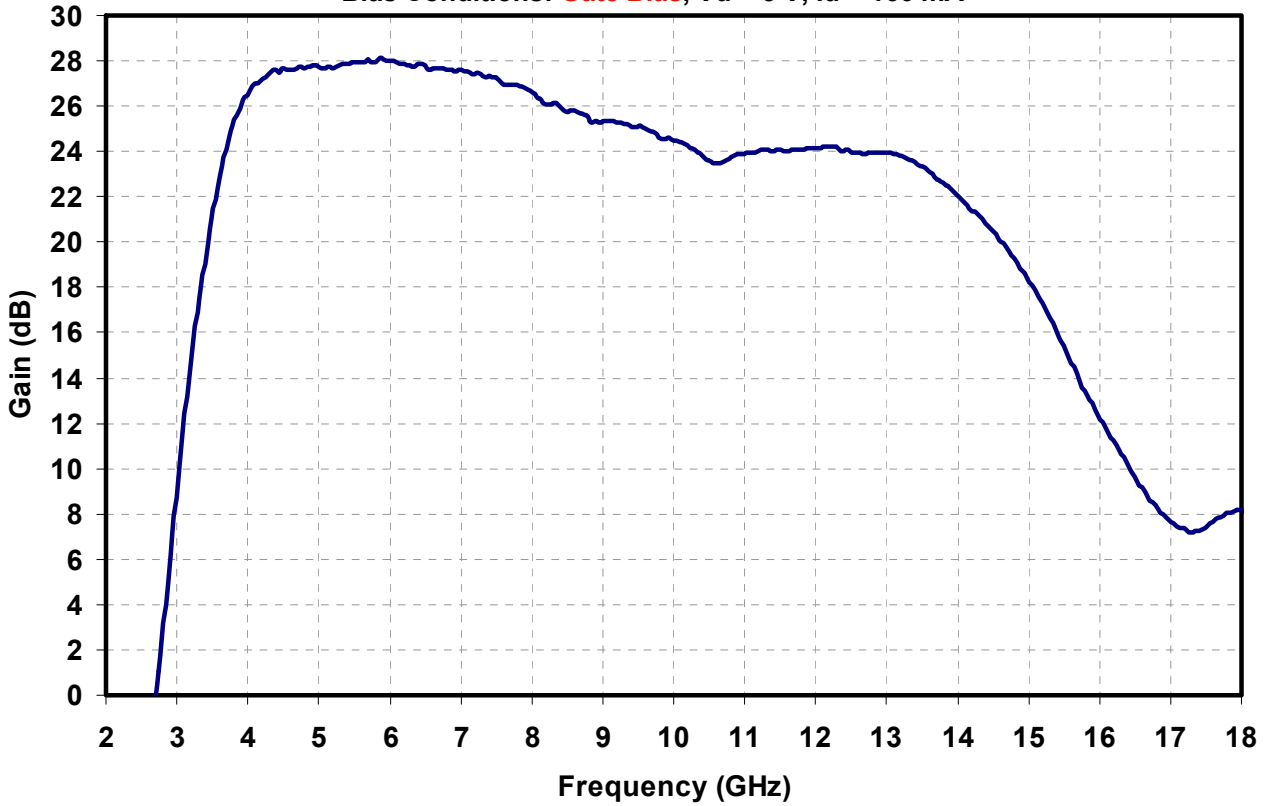
Measured Data

Bias Conditions: **Self Bias**, $V_d = 5\text{ V}$, $I_d = 90\text{ mA}$



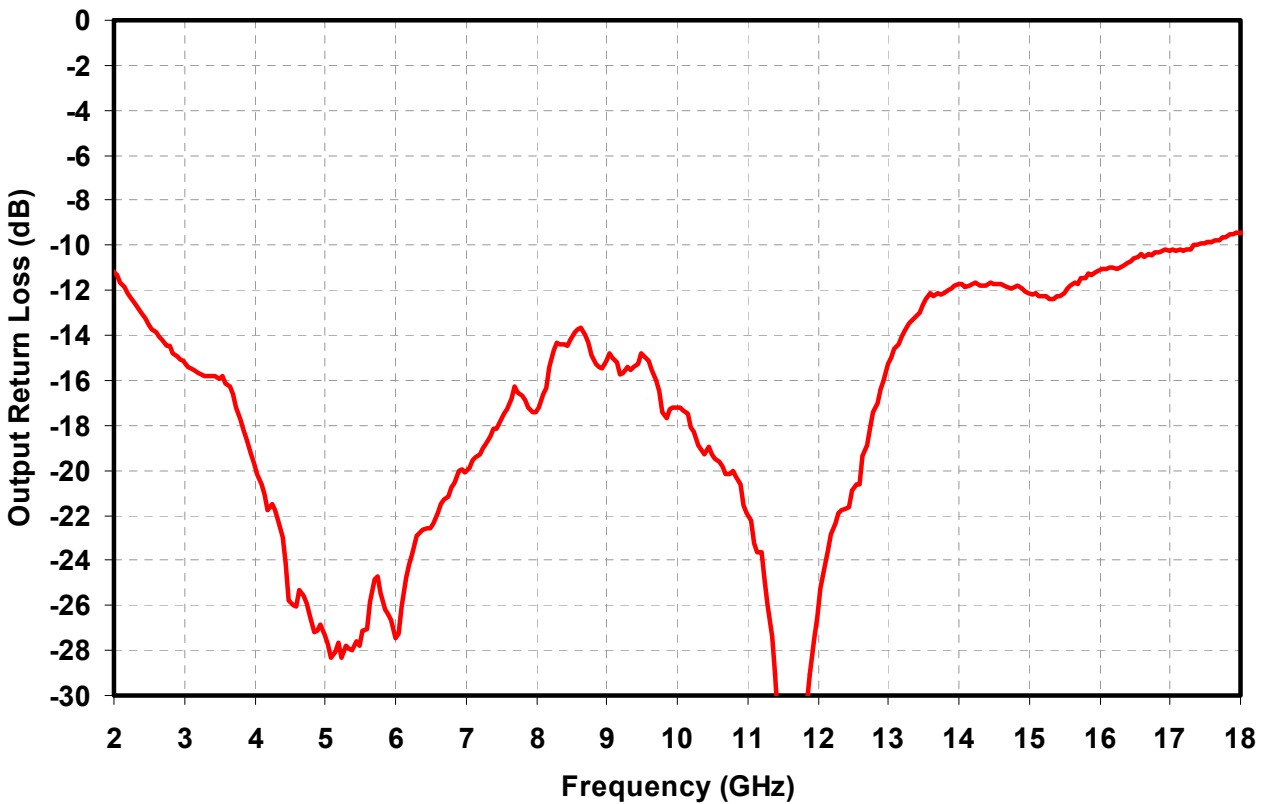
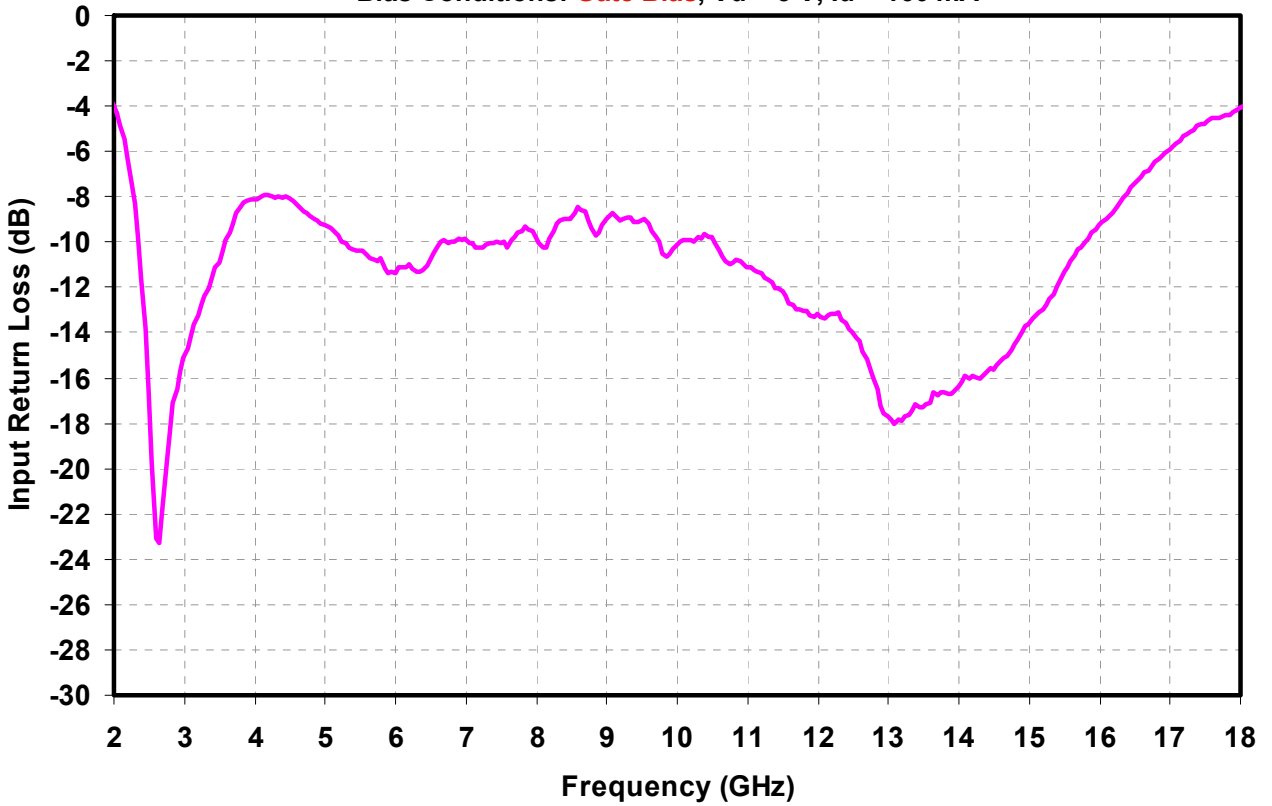
Measured Data

Bias Conditions: **Gate Bias**, $V_d = 5\text{ V}$, $I_d = 160\text{ mA}$



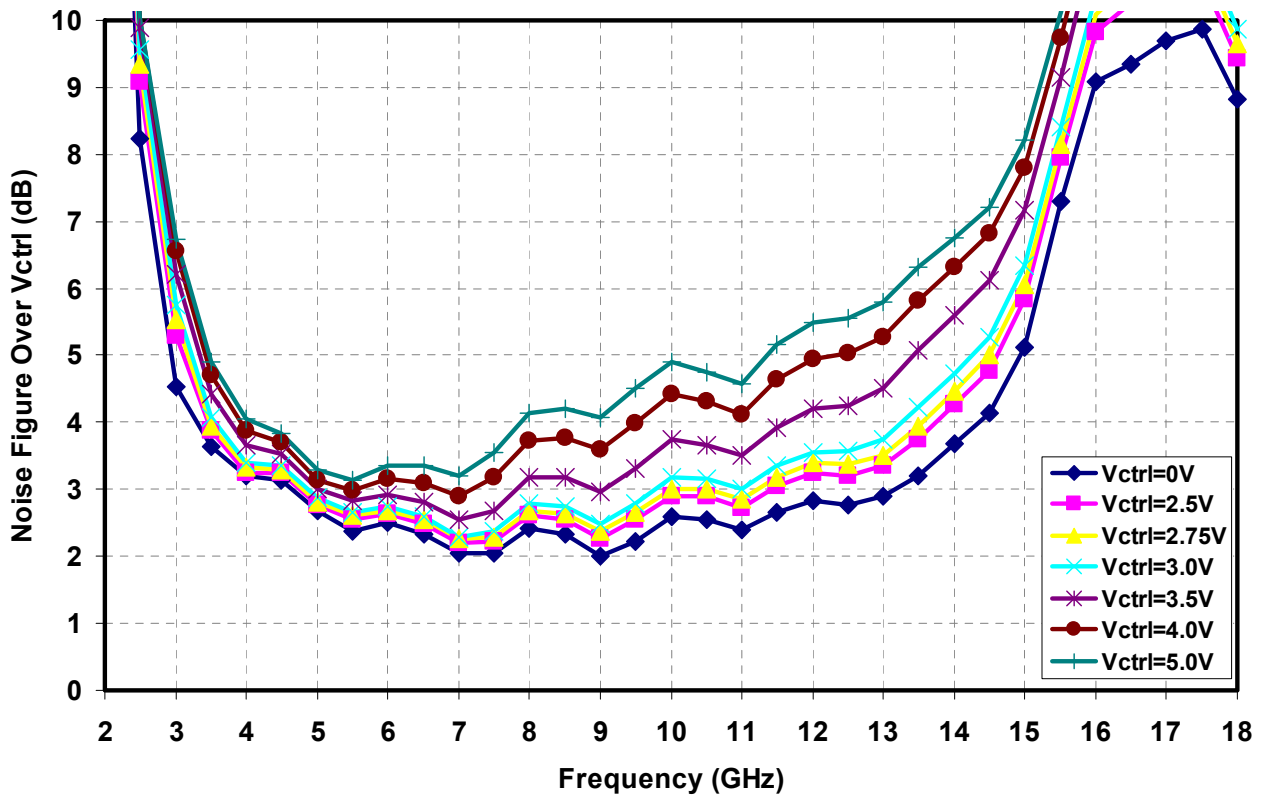
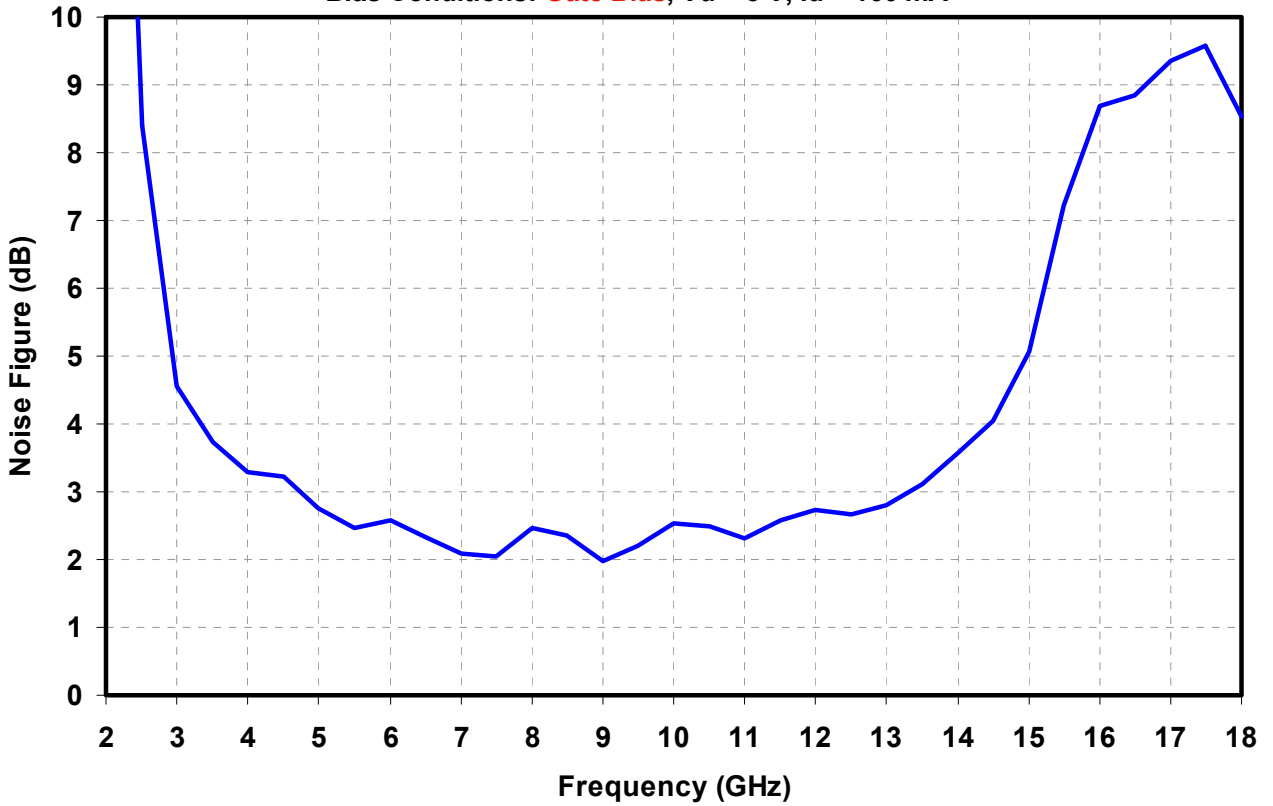
Measured Data

Bias Conditions: **Gate Bias**, $V_d = 5\text{ V}$, $I_d = 160\text{ mA}$



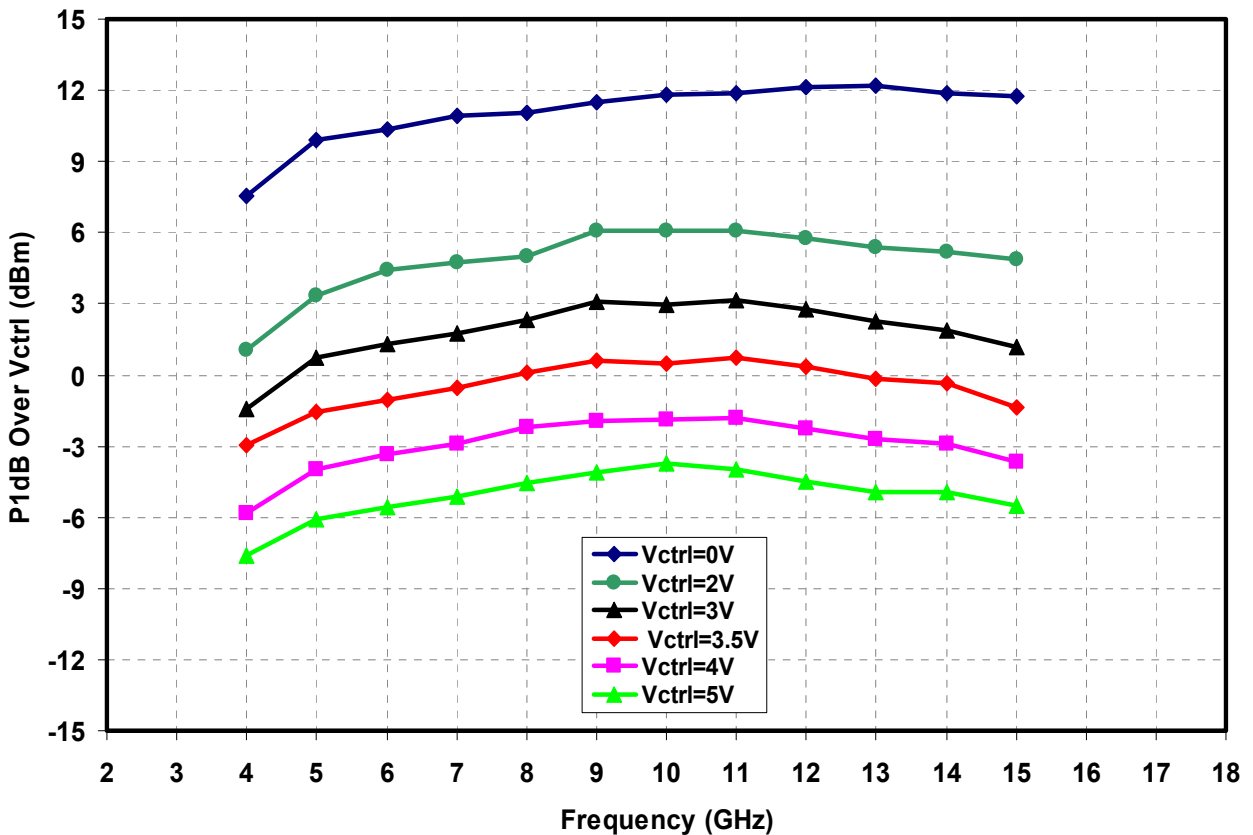
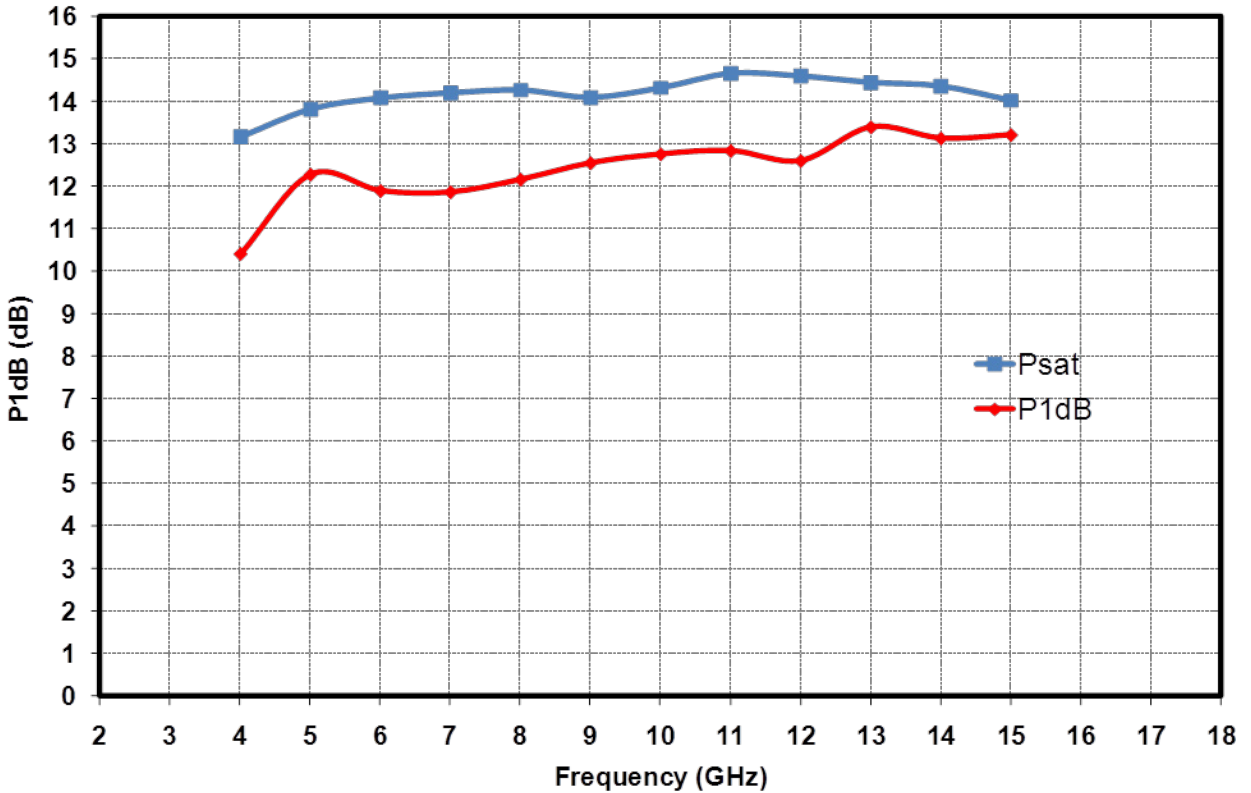
Measured Data

Bias Conditions: **Gate Bias**, $V_d = 5\text{ V}$, $I_d = 160\text{ mA}$



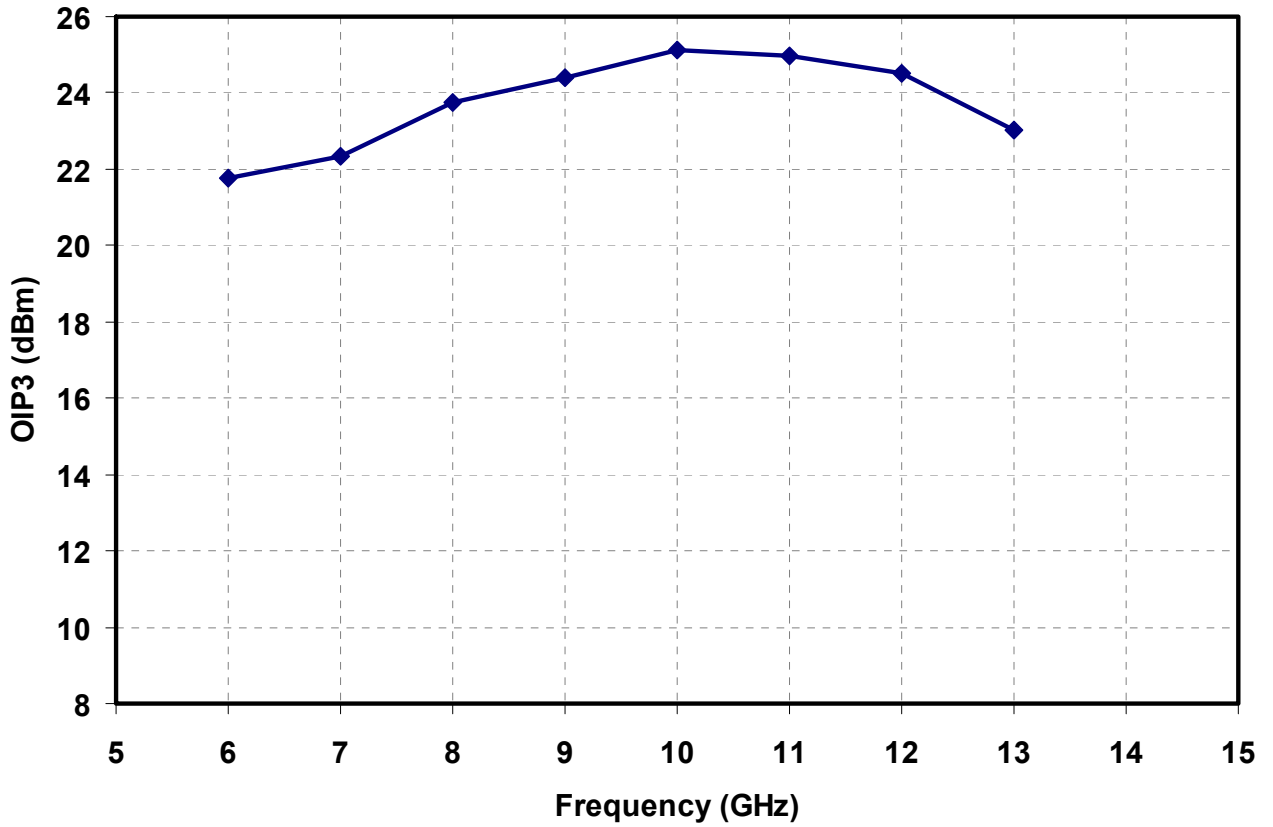
Measured Data

Bias Conditions: **Gate Bias**, $V_d = 5\text{ V}$, $I_d = 160\text{ mA}$

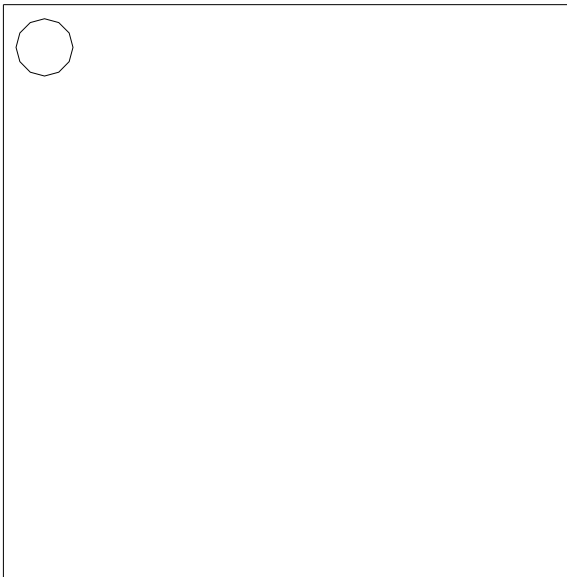


Measured Data

Bias Conditions: **Gate Bias**, $V_d = 5\text{ V}$, $I_d = 160\text{ mA}$

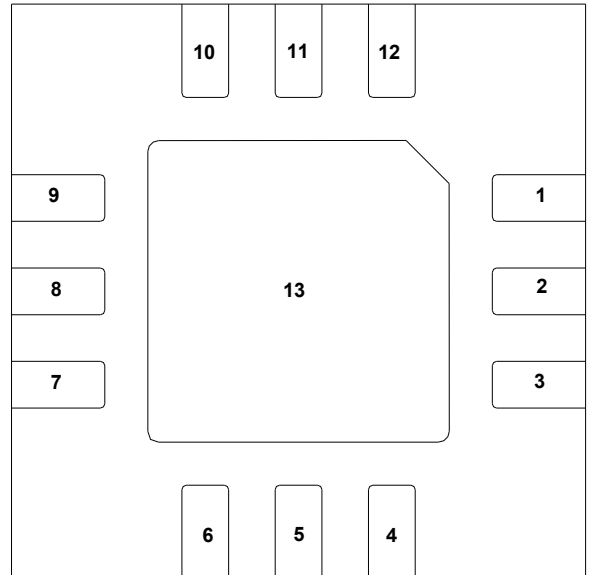


Package Pinout Diagram



Top View

Dot indicates Pin 1



Bottom View

Self Bias

Pin	Description
1,3, 4, 5, 6, 7, 9, 12	NC
2	RF Input
8	RF Output
10	Vd
11	Vctrl
13	Gnd

Self Bias: Vd = 5V (Id = ~90mA), Vctrl = 0 to +5V for Gain adjustment

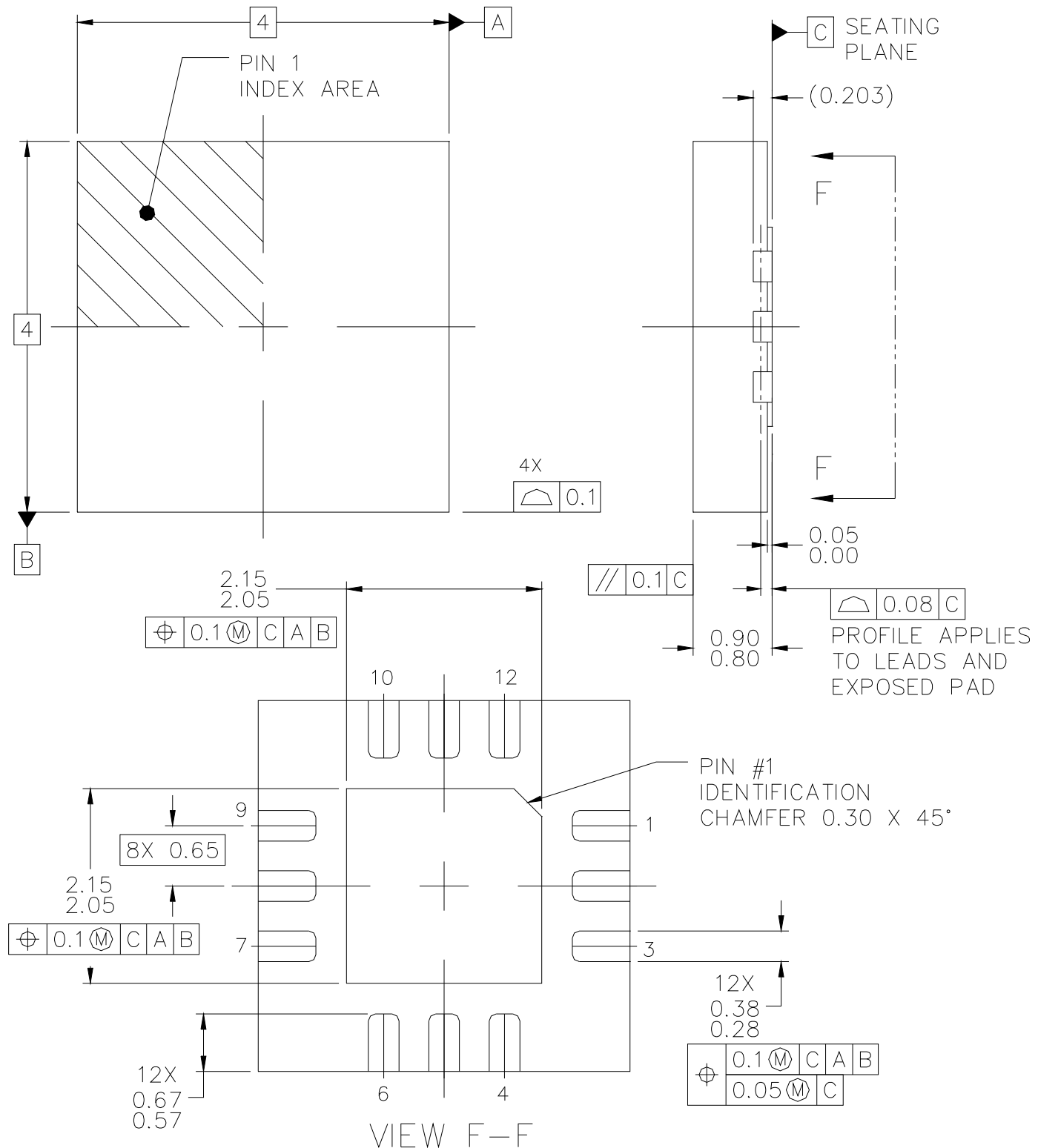
Gate Bias

Pin	Description
1,3, 4, 5, 6, 7, 9	NC
2	RF Input
8	RF Output
10	Vd
11	Vctrl
12	Vg
13	Gnd

Gate Bias: Vd = 5V , Vctrl = 0 to +5V for Gain adjustment
Vg = Range, -0.5 to 0, typically ~ -0.1 will provide ~160mA of Id.

Mechanical Drawing

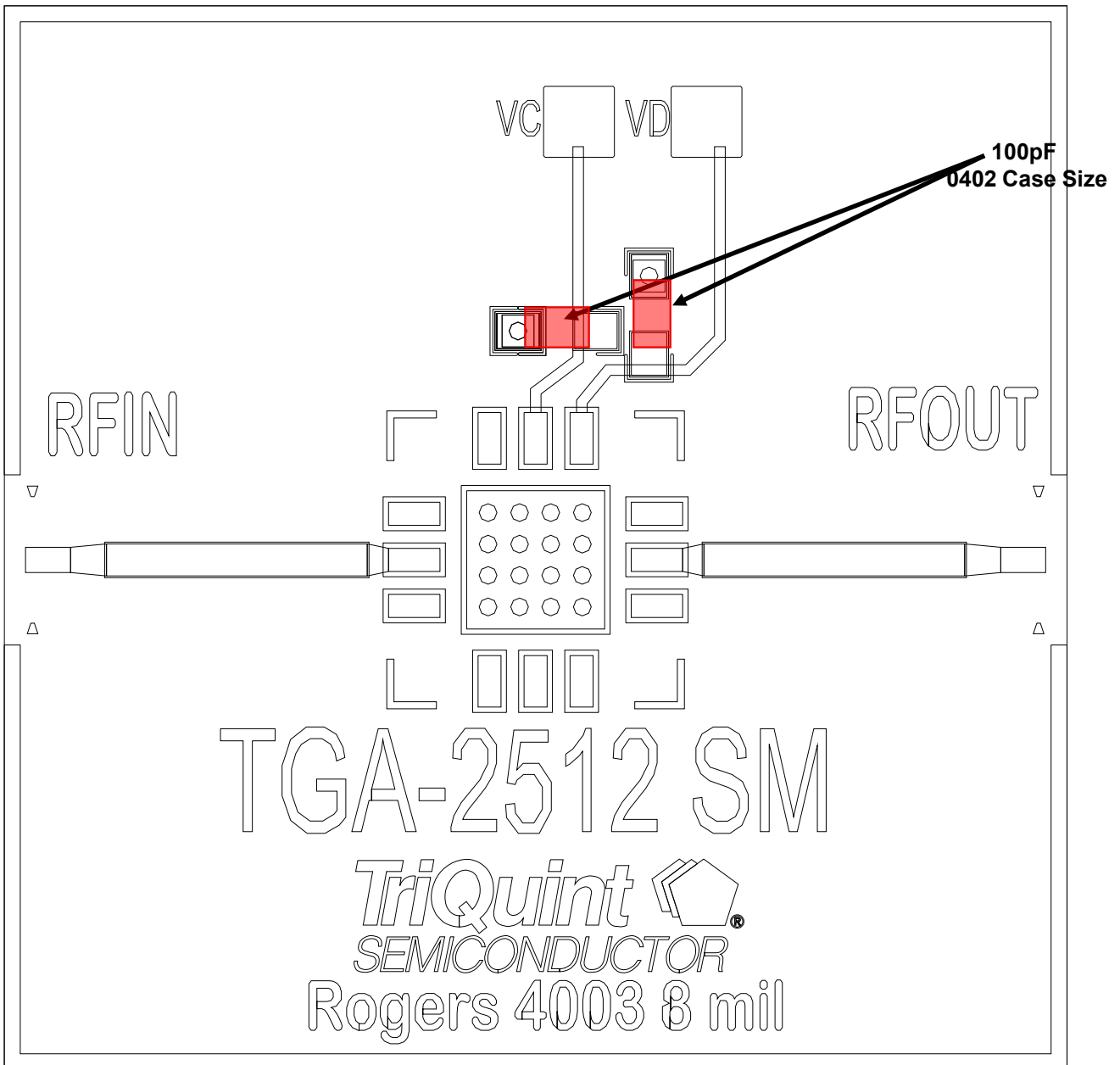
Units: Millimeters



GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.

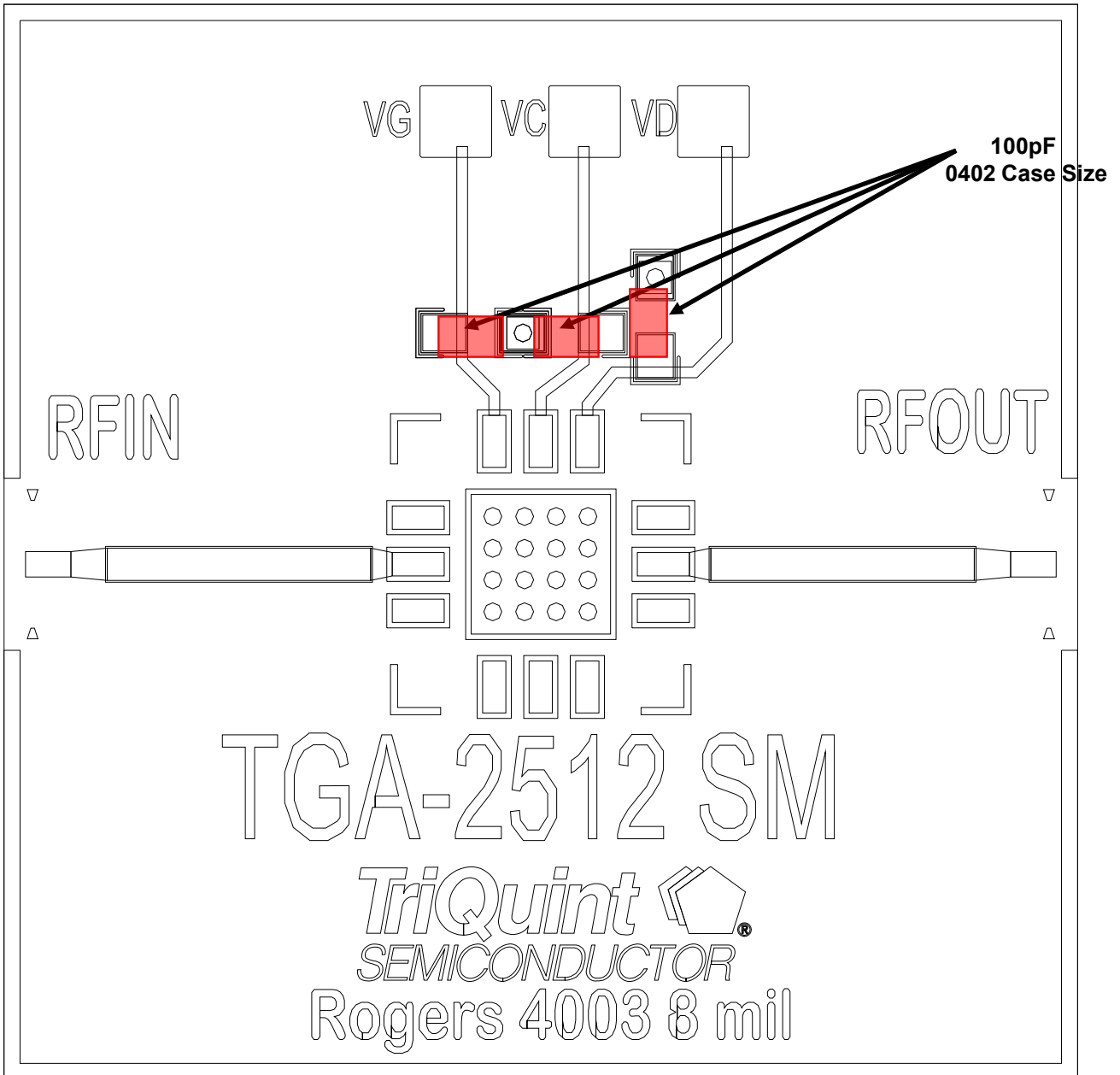
Recommended Board Layout Assembly

Self Bias



Recommended Board Layout Assembly

Gate Bias



Ordering Information

Part	Package Style
TGA2512-1-SM	QFN 4x4 Surface Mount – Self Bias
TGA2512-2-SM	QFN 4x4 Surface Mount – Gate Bias